

6.2 noise analysis

Why do you need noise analysis ?

Equivalent input noise voltage of amp:

determines

the minimum input voltage of amp that can be amplified

(the min detectable signal)

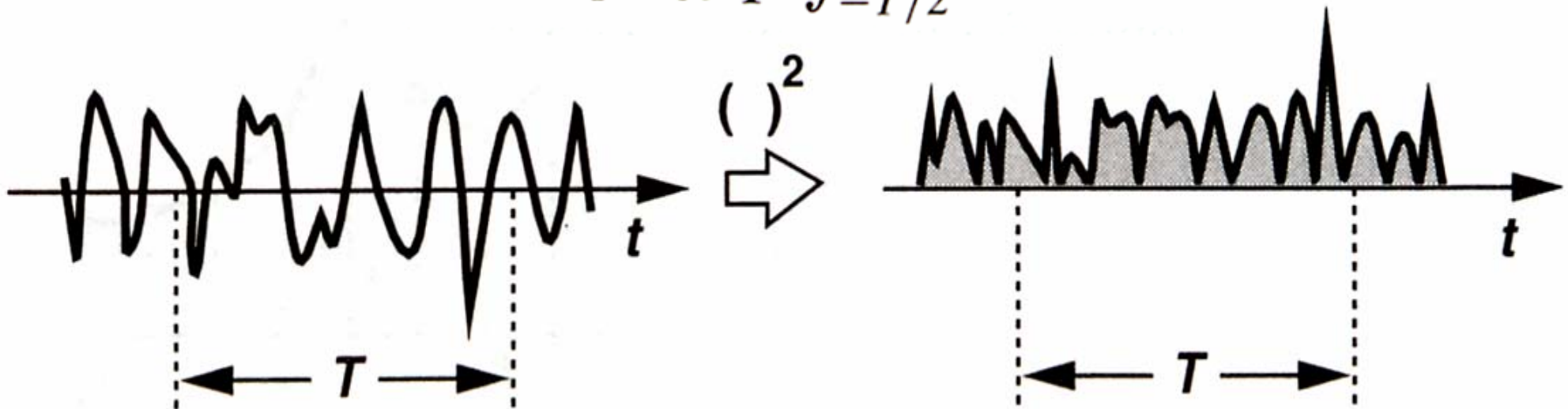
1. What is noise ?
2. Noise of resistor
3. kT / C noise
4. Noise BW
5. MOSFET noise
6. Equivalent input noise voltage (concept, MOSFET)

Noise: random process

(instantaneous value in time domain cannot be predicted)

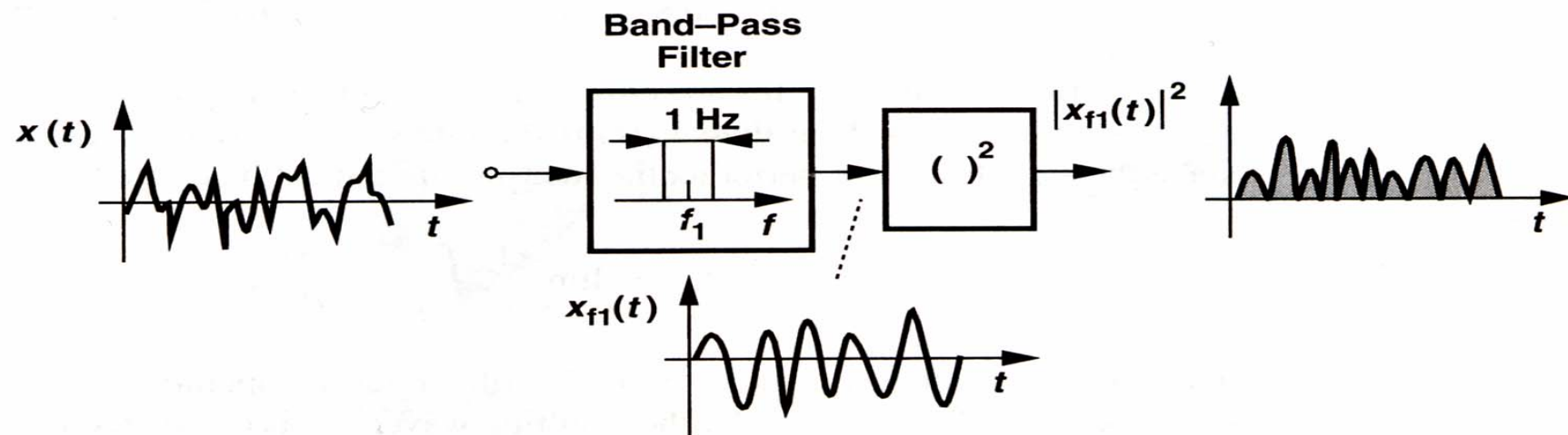
Noise: Average power (P_{av}) can be predicted

$$P_{av} = \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-T/2}^{+T/2} x^2(t) dt$$

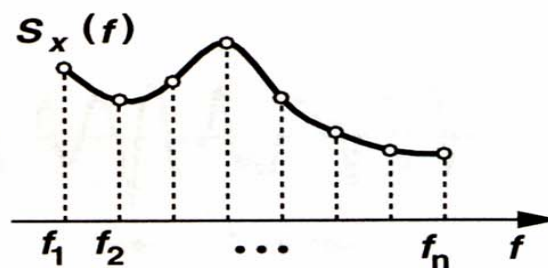


Power spectral density (PSD) $S_x(f)$:

Average power in one-Hertz bandwidth around frequency f



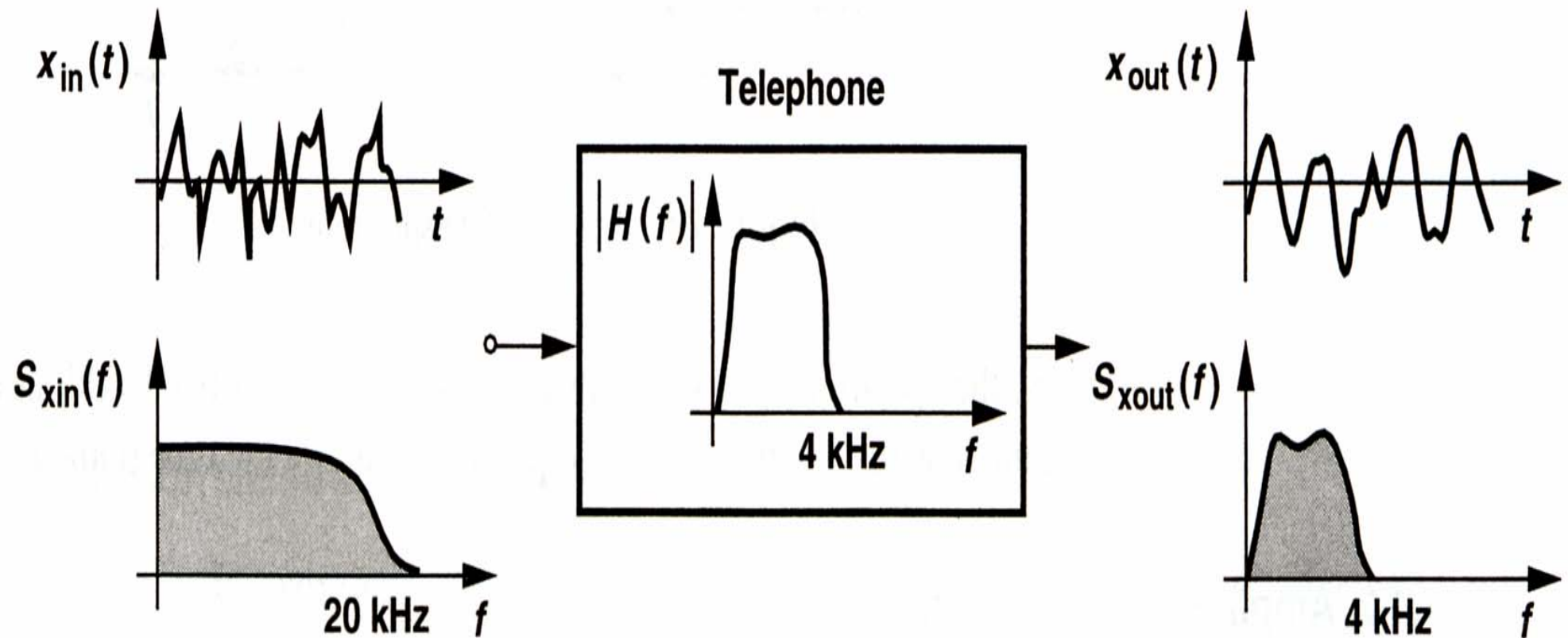
(a)



(b)

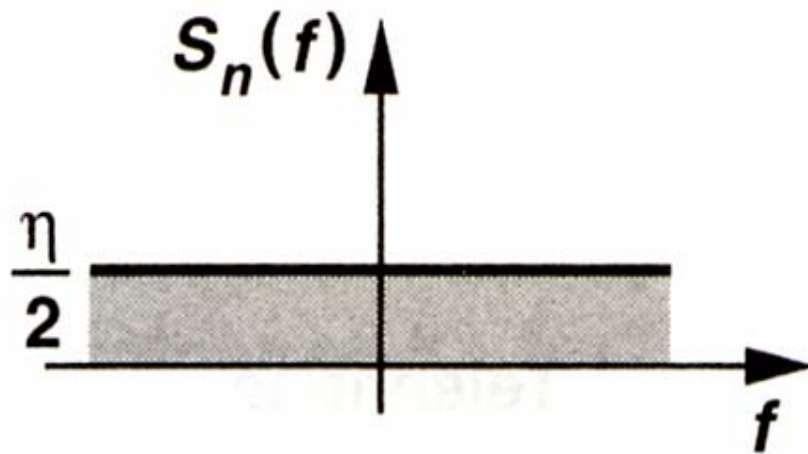
LTI (linear time invariant) system with transfer function $H(f)$

$$S_Y(f) = S_X(f)|H(f)|^2$$

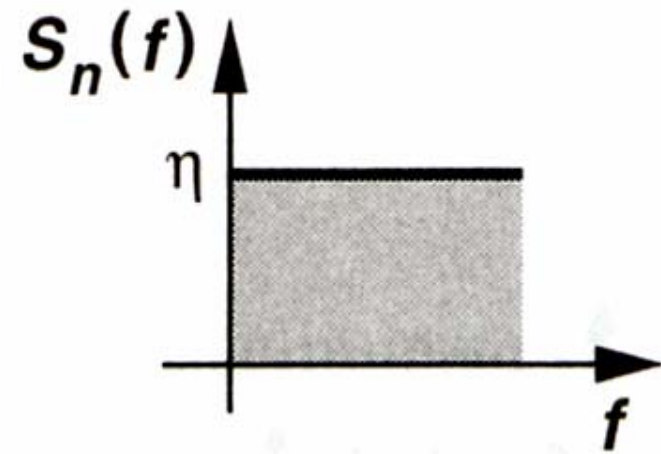
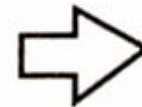


Power spectral density (PSD) $S_n(f)$: Even function of f

$$|V_n|^2 (\text{Power}) = \int S_n(f) df$$



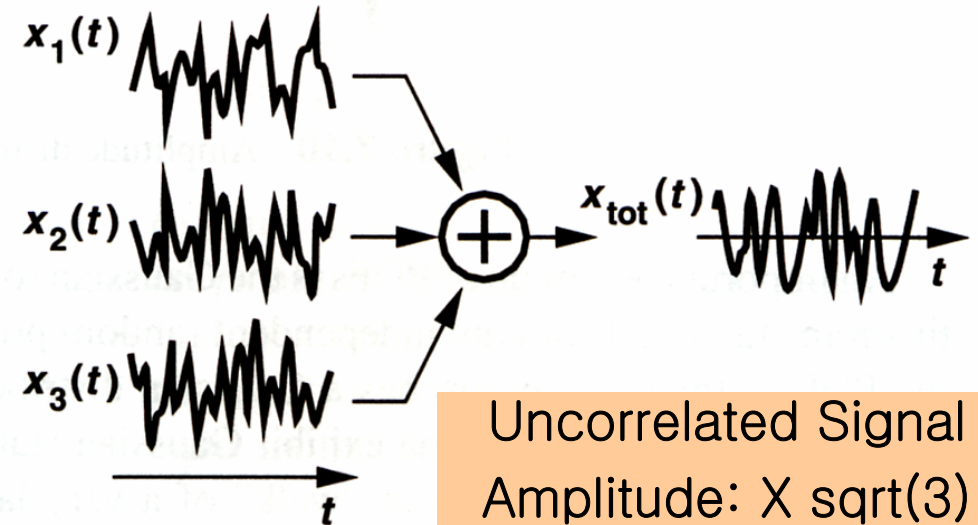
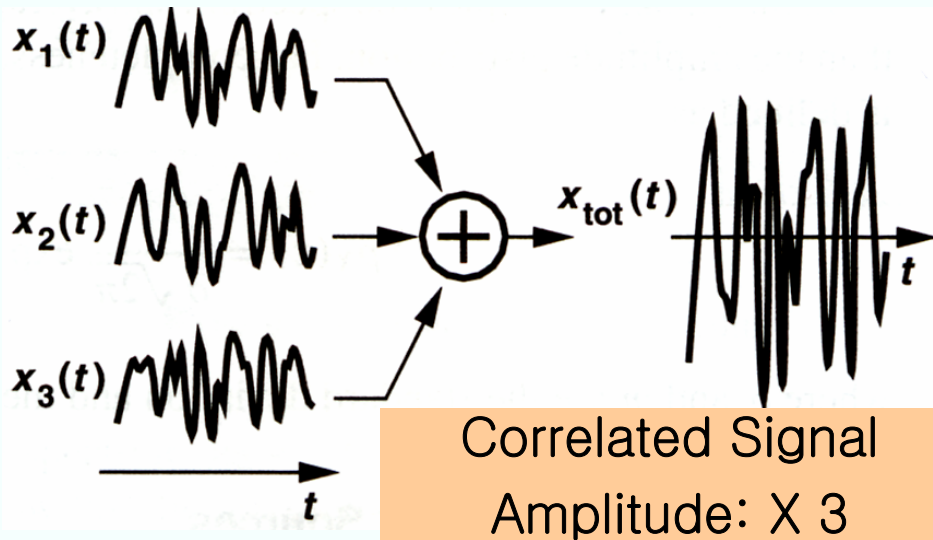
Two-sided PSD



One-sided PSD

Can use either of these two
(keep power the same)

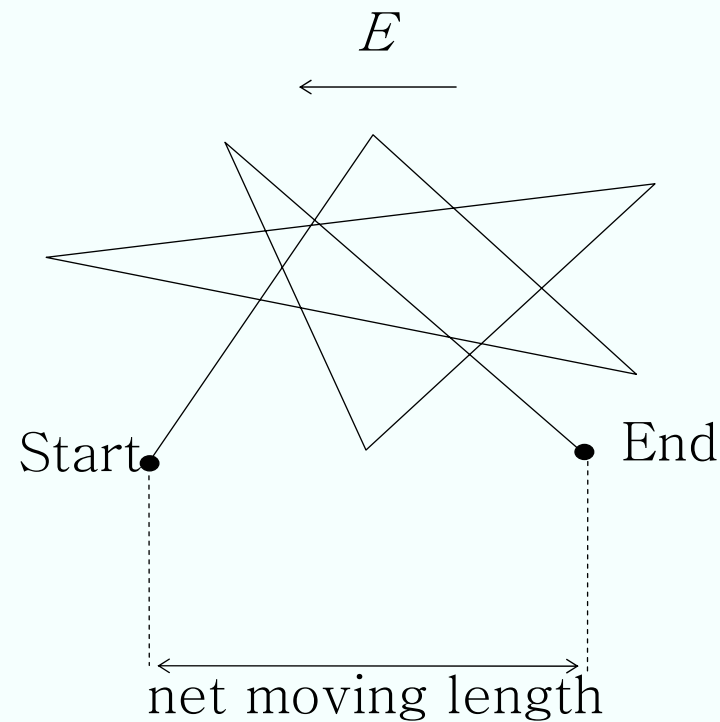
Correlated vs Uncorrelated signals



$$\begin{aligned}
 P_{av} &= \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-T/2}^{+T/2} [x_1(t) + x_2(t)]^2 dt \\
 &= \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-T/2}^{+T/2} x_1^2(t) dt + \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-T/2}^{+T/2} x_2^2(t) dt \\
 &\quad + \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-T/2}^{+T/2} 2x_1(t)x_2(t) dt \\
 &= P_{av1} + P_{av2} + \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-T/2}^{+T/2} 2x_1(t)x_2(t) dt,
 \end{aligned}$$

6.2.1 thermal noise of resistor

Thermal energy of an electron : kT
→ Random motion



$$\frac{1}{2} \cdot m \cdot v_{th}^2 = \frac{3}{2} \cdot kT$$

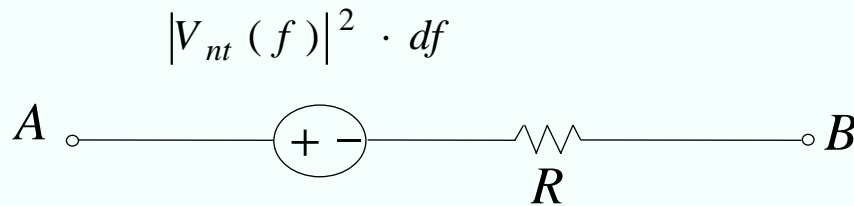
Fig 6.2.1 Motion of an electron inside a resistor

$$\overline{v_{nt}^2} \triangleq \lim_{T \rightarrow \infty} \frac{1}{T} \cdot \int_0^T \{v_{nt}(t)\}^2 \cdot dt = \int_0^\infty |V_{nt}(f)|^2 \cdot df$$

$$|V_{nt}(f)|^2 = 4kTR$$

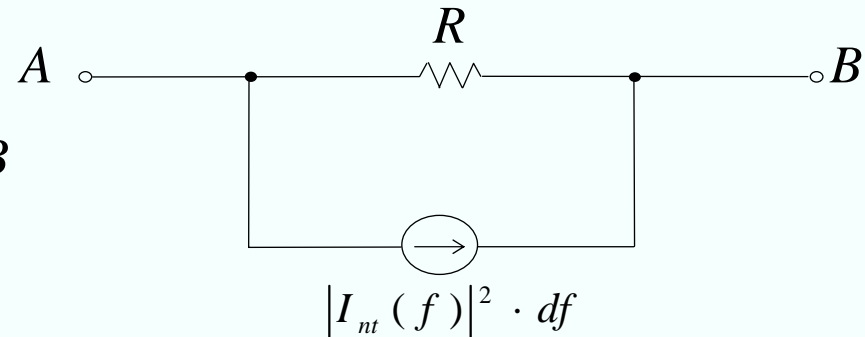
1-sided PSD

$$|I_{nt}(f)|^2 = \frac{|V_{nt}(f)|^2}{R^2} = \frac{4kT}{R}$$



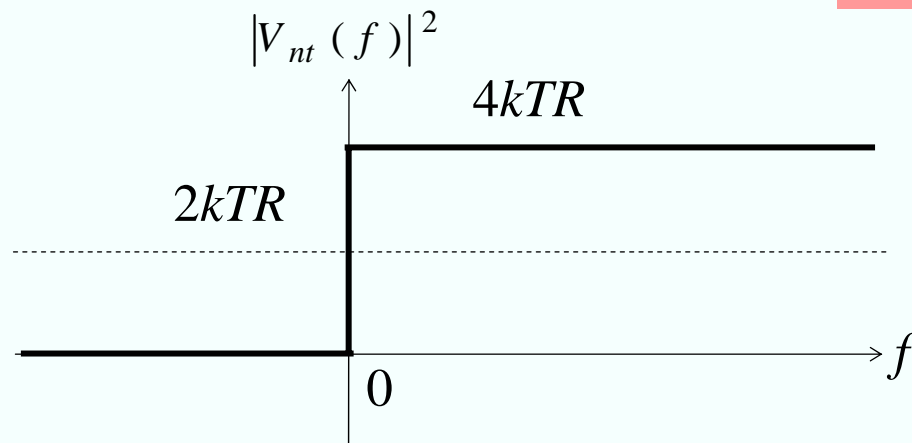
(a) Thevenin form

$$|V_{nt}(f)|^2 = 4kTR$$



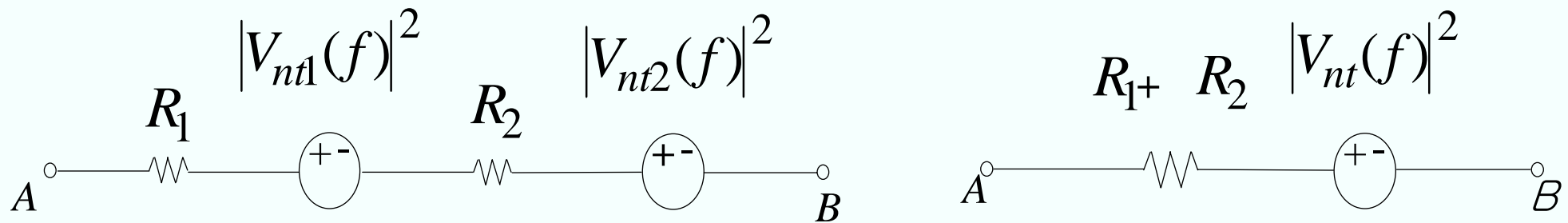
(b) Norton form

$$|I_{nt}(f)|^2 = \frac{|V_{nt}(f)|^2}{R^2} = \frac{4kT}{R}$$



(c) Frequency spectrum of thermal noise voltage variance

(Solid: one-sided PSD, $f > 0$ only, Dotted: two-sided PSD)

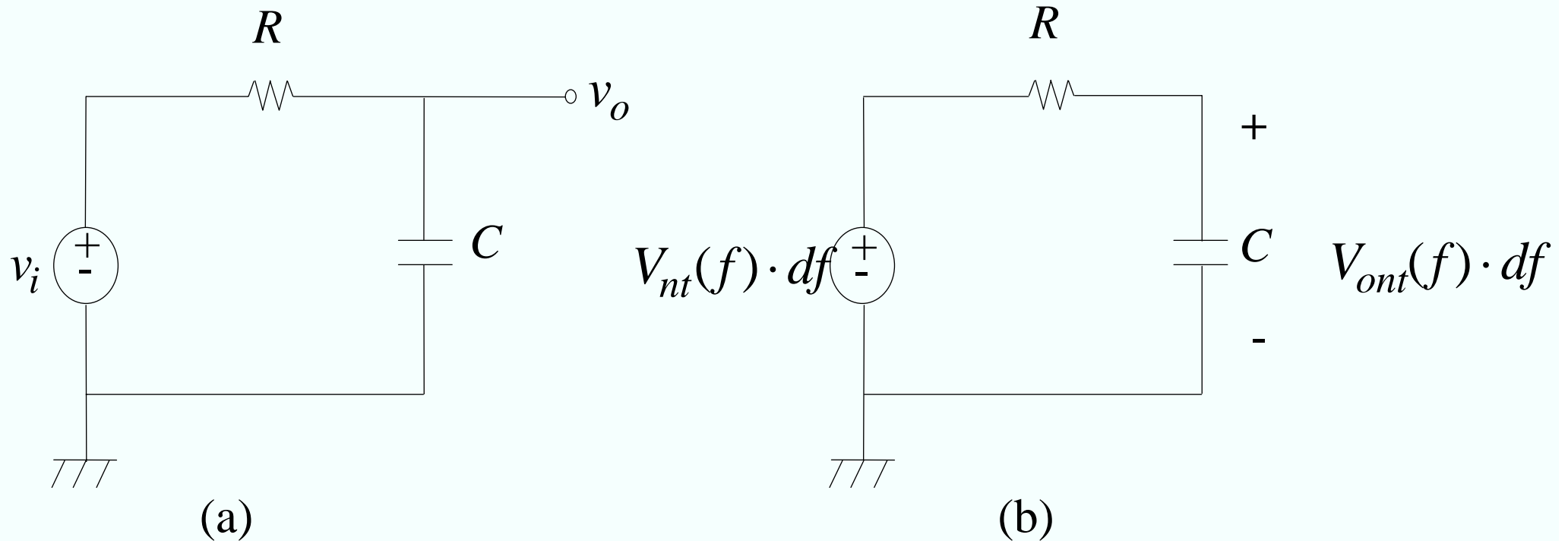


$$\overline{v_{nt}^2} = \lim_{T \rightarrow \infty} \frac{1}{T} \int_0^T (v_{nt1}(t) + v_{nt2}(t) - 0)^2 \cdot dt$$

$$\lim_{T \rightarrow \infty} \frac{1}{T} \int_0^T (v_{nt1}(t) \cdot v_{nt2}(t)) \cdot dt = 0 \quad \leftarrow \text{uncorrelated}$$

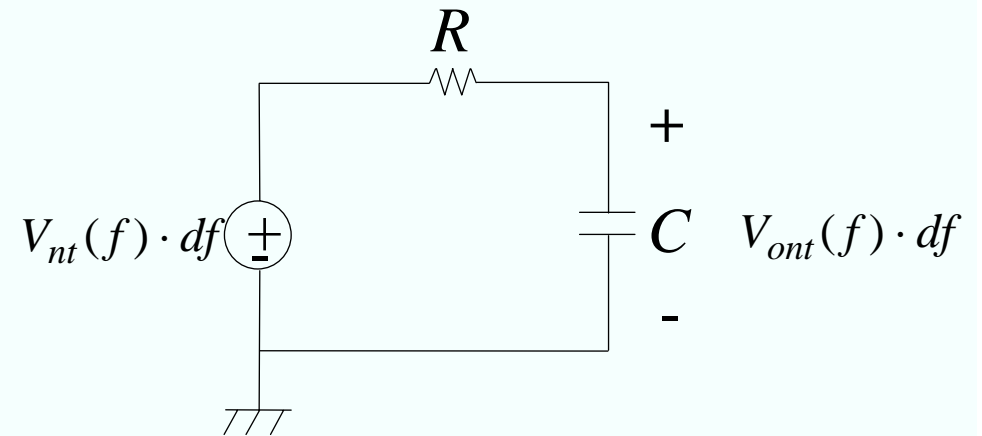
$$\overline{v_{nt}^2} = \overline{v_{nt1}^2} + \overline{v_{nt2}^2}$$

$$|V_{nt}(f)|^2 = |V_{nt1}(f)|^2 + |V_{nt2}(f)|^2 = 4kT \cdot (R_1 + R_2)$$

6.2.2 kT / C noise**Fig 6.2.4 Output noise spectrum of RC low pass filter**

$$H(f) = \frac{1}{1 + j \cdot \frac{f}{f_c}}$$

$$V_{ont}(f) = V_{nt}(f) \cdot H(f)$$



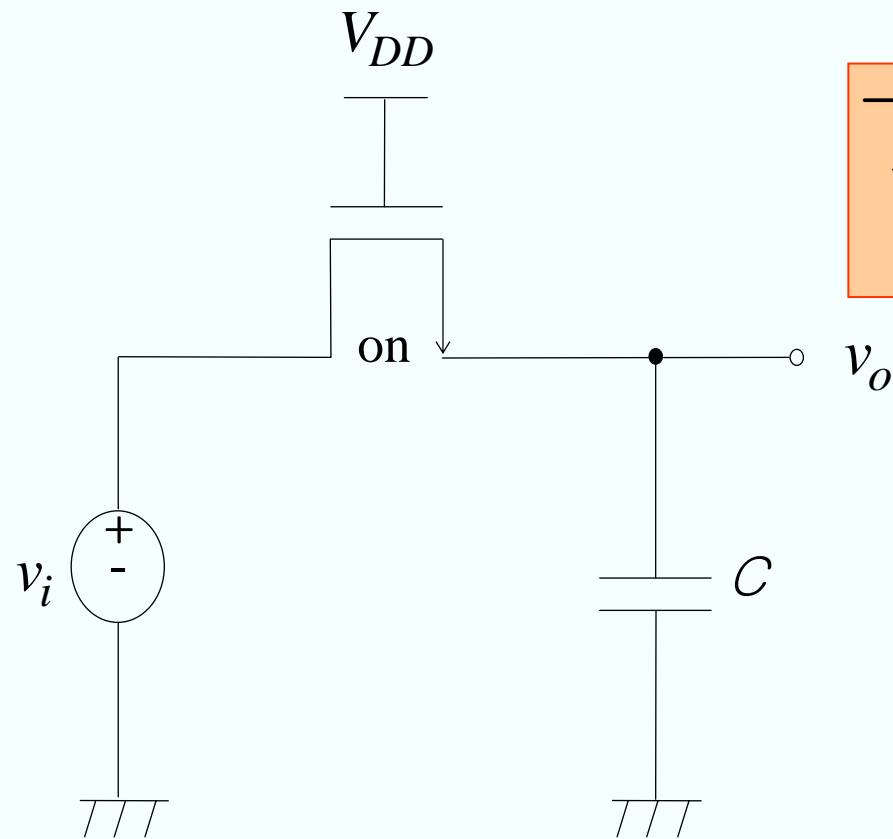
$$\overline{v_{ont}^2} = \int_0^\infty |V_{ont}(f)|^2 df = \int_0^\infty |H(f)|^2 \cdot |V_{nt}(f)|^2 \cdot df$$

$$= 4kTR \cdot \int_0^\infty |H(f)|^2 df = 4kTR \cdot \int_0^\infty \frac{1}{1 + (f/f_c)^2} df$$

$$\overline{v_{ont}^2} = \frac{kT}{C}$$

$$v_{ont} = \sqrt{\frac{kT}{C}}$$

$$N_e \text{ (Number of electrons)} = \sqrt{kTC}/q$$



$$\overline{v_{out}^2} = \frac{kT}{C}$$

Fig 6.2.5 Sampling circuit using MOS switch

Noise bandwidth : NBW

$$\overline{v_{ont}^2} = |V_{ont}(0)|^2 \cdot NBW = 4kTR \cdot NBW = \frac{kT}{C}$$

$$NBW = \frac{\int_0^{\infty} |H(f)|^2 df}{|H(0)|^2} = \frac{\pi}{2} \cdot f_c$$

Single-pole

$$H(f) = \frac{1}{1 + j \cdot \frac{f}{f_c}}$$

6.2.3 Noise model of MOS transistor

MOSFET thermal noise

$$|I_{dnt}(f)|^2 = \frac{4kT}{R_{avg}} \quad \leftarrow \text{Drain noise current spectral density}$$

$$R_{avg} = \frac{L}{W \cdot \sigma_{avg}} \quad \leftarrow \text{Average channel resistance}$$

$$\sigma_{avg} = \frac{1}{L} \cdot \int_0^L \sigma(y) dy = \frac{1}{L} \cdot \int_0^L \mu_n \cdot q_N(y) dy$$

$$q_N(y) = C_{ox} \cdot (V_{GS} - V_{TH}) \cdot \sqrt{1 - (y/L)}$$

$$\sigma_{avg} = \frac{1}{L} \cdot \int_0^L \sigma(y) dy = \frac{1}{L} \cdot \int_0^L \mu_n \cdot q_N(y) dy$$

$$\sigma_{avg} = \frac{2}{3} \cdot \mu_n C_{ox} \cdot (V_{GS} - V_{TH}) \quad R_{avg} = \frac{3}{2} \cdot \frac{L}{W} \cdot \frac{1}{\mu_n C_{ox} (V_{GS} - V_{TH})}$$

$$|I_{dnt}(f)|^2 = \frac{4kT}{R_{avg}}$$

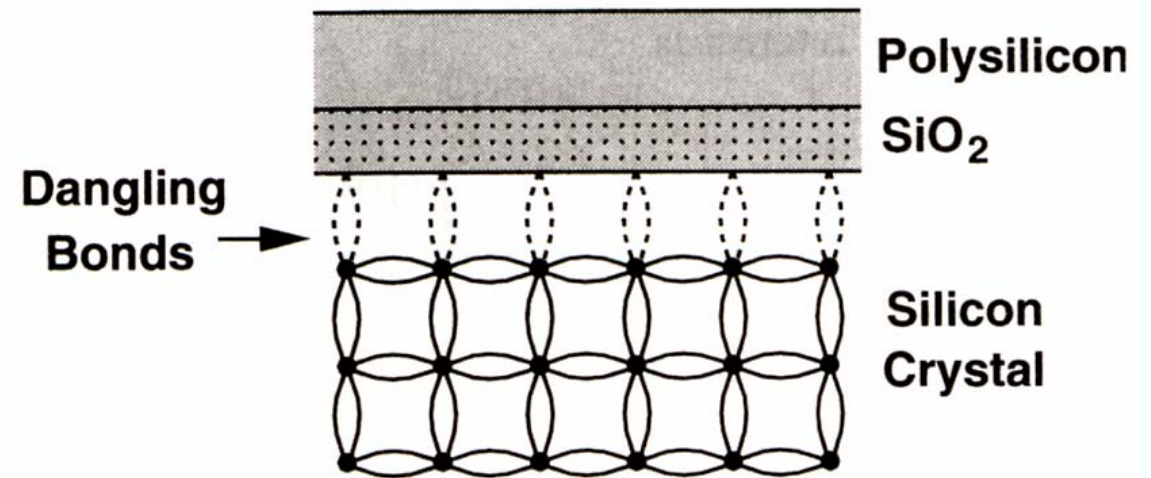
$$|I_{dnt}(f)|^2 = \left(\frac{8kT}{3} \right) \cdot \mu_n C_{ox} \cdot \frac{W}{L} \cdot (V_{GS} - V_{TH})$$

$$|I_{dnt}(f)|^2 = \left(\frac{8kT}{3} \right) \cdot g_m = 4kT \cdot \frac{2}{3} \cdot g_m$$

Equip noise R = 1.5/gm

Short channel: 2/3 → 2.5 at 0.25μm

MOSFET flicker noise



$$|I_{dn}(f)|^2 = |I_{dnt}(f)|^2 + |I_{dnf}(f)|^2$$

$$|I_{dn}(f)|^2 = \frac{8kT}{3} \cdot g_m + \frac{KF \cdot I_D^{AF}}{f}$$

MOSFET flicker noise models

$$|I_{dn}(f)|^2 = \frac{8kT}{3} \cdot g_m + \frac{KF \cdot I_D^{AF}}{f}$$

$$|I_{dn}(f)|^2 = \frac{8kT}{3} \cdot g_m + \frac{K}{W L C_{ox} \cdot f} \cdot g_m^2$$

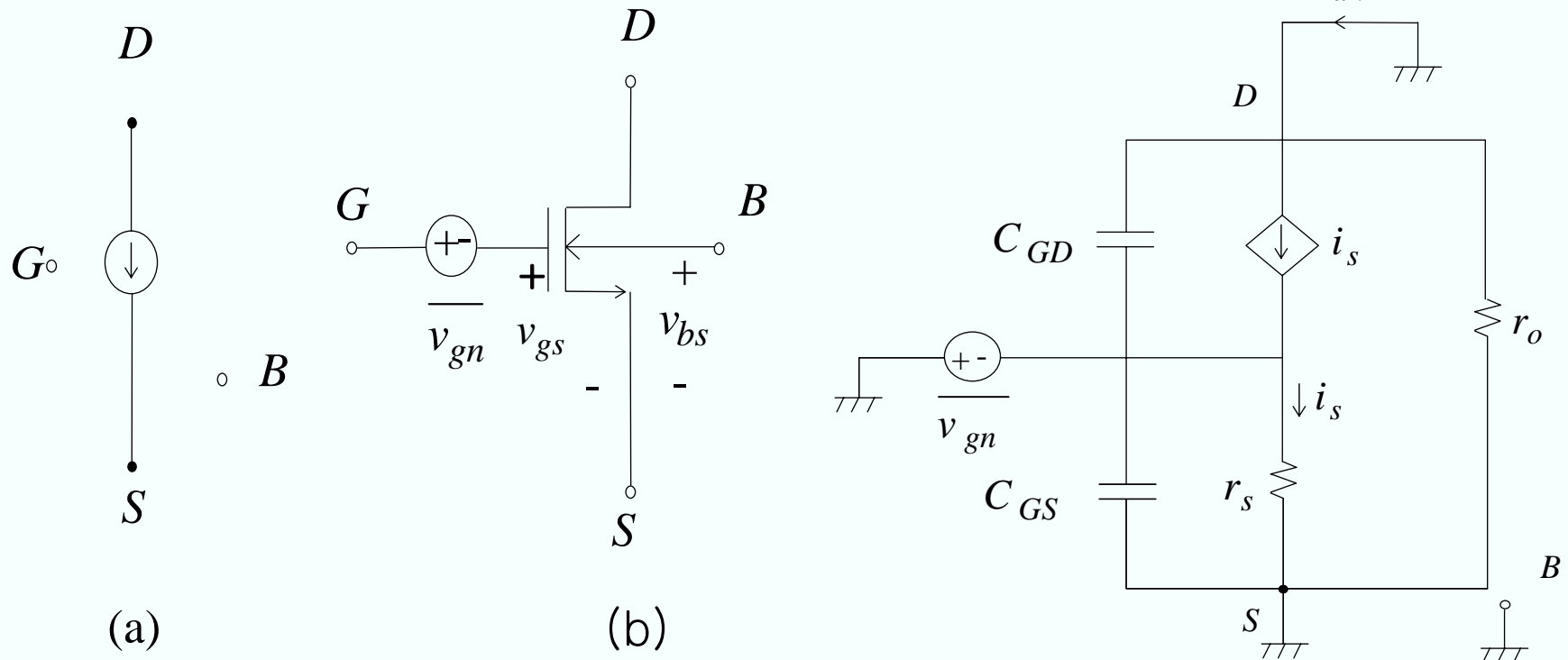
$$\overline{i_{dnf}^2(f)} = \frac{KF \cdot I_D^{AF}}{WLC_{ox} \cdot f^{EF}} \quad \text{Flicker noise}$$

$$\overline{i_{dnt}^2(f)} = \frac{8}{3} \cdot kT \cdot (g_m + g_{mb} + g_{ds}) \quad \text{Thermal noise}$$

Example of noise model parameter values

	NMOS	PMOS
KF	3.76×10^{-25}	7.58×10^{-25}
AF	9.70×10^{-1}	1.67
EF	1.31	1.12

Equivalent noise voltage of MOSFET



$$\overline{i_{dn}} = -(g_m + j2\pi f \cdot C_{GD}) \cdot \overline{v_{gn}}$$

$$\overline{i_{dn}} \approx -g_m \cdot \overline{v_{gn}}$$

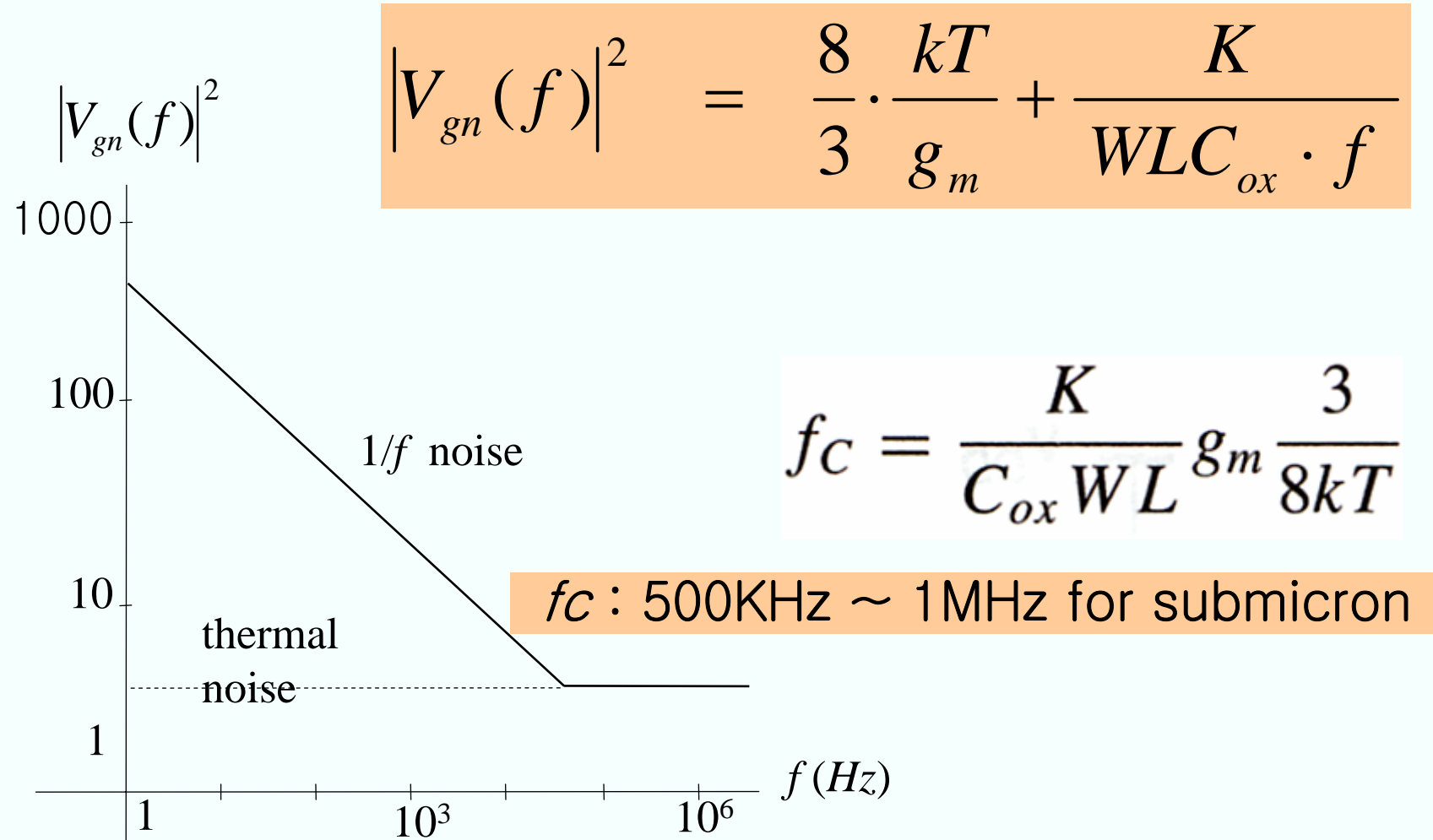
$$\overline{v_{gn}^2} = \frac{\overline{i_{dn}^2}}{g_m^2}$$

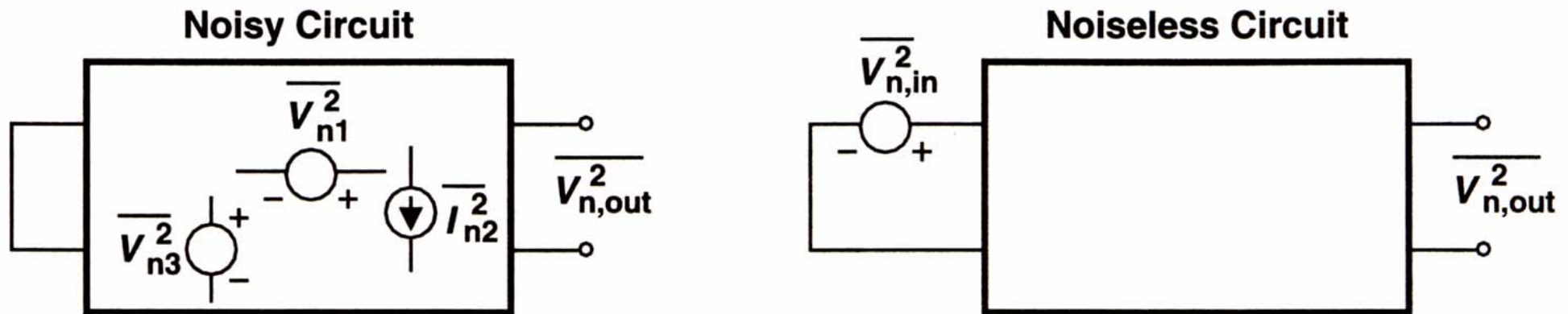
$$\overline{v_{gn}^2} = \frac{\overline{i_{dn}^2}}{g_m^2}$$

$$\overline{i_{dn}} = \sqrt{\overline{i_{dn}^2}} = \sqrt{\int_0^\infty |I_{dn}(f)|^2 df}$$

$$|V_{gn}(f)|^2 = \frac{|I_{dn}(f)|^2}{g_m^2} = \frac{8}{3} \cdot \frac{kT}{g_m} + \frac{KF \cdot I_D^{AF}}{f \cdot g_m^2}$$

$$|V_{gn}(f)|^2 = \frac{8}{3} \cdot \frac{kT}{g_m} + \frac{K}{W L C_{ox} \cdot f}$$

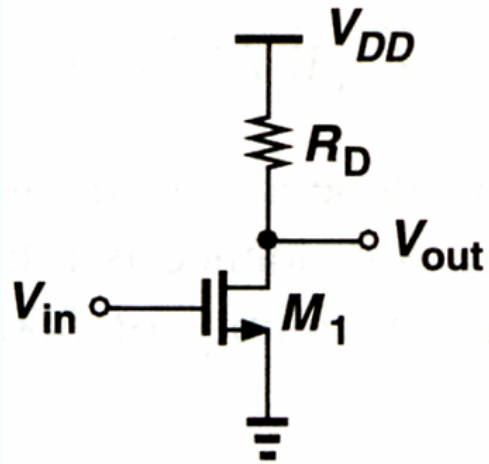
Fig. 6.2.7 MOSFET $1/f$ noise spectrum



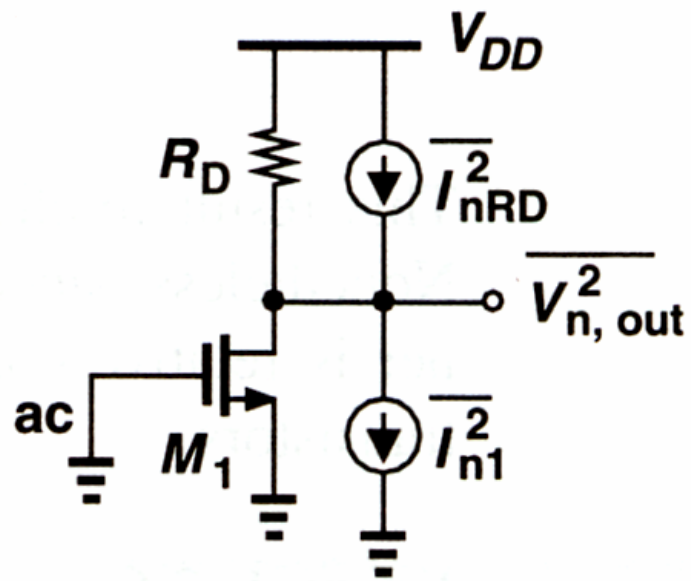
Equivalent input referred noise voltage determines

Min input voltage that can be amplified
(min detectable input voltage)

6.2.4 Input referred noise voltage of single stage amp

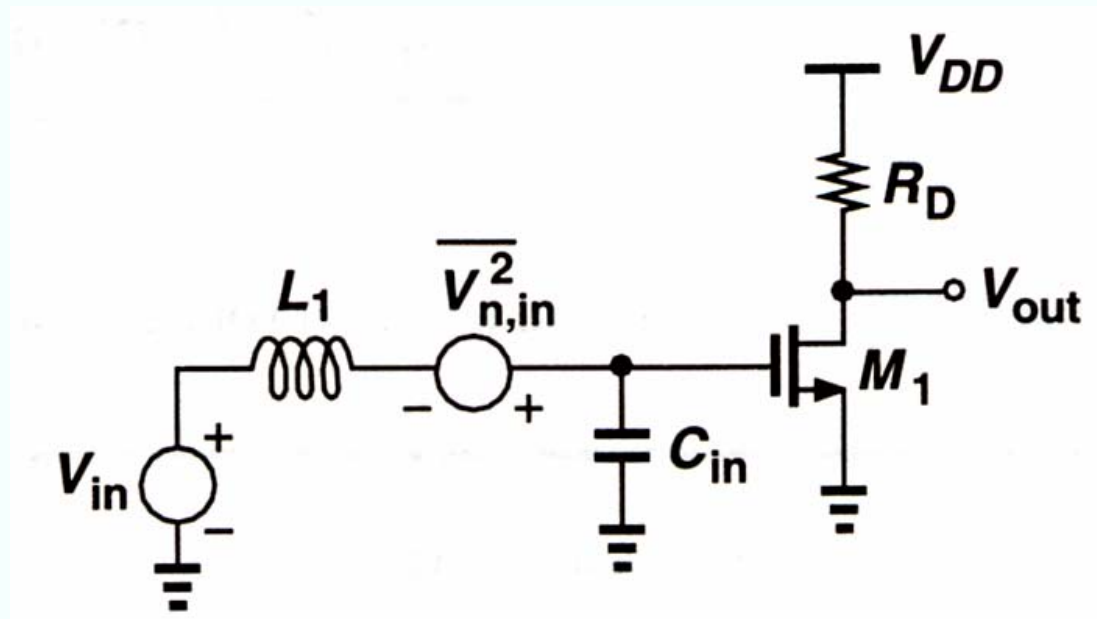


$$\overline{V_{n,out}^2} = \left(4kT \frac{2}{3} g_m + \frac{K}{C_{ox} W L} \cdot \frac{1}{f} \cdot g_m^2 + \frac{4kT}{R_D} \right) R_D^2$$



$$\begin{aligned} \overline{V_{n,in}^2} &= \frac{\overline{V_{n,out}^2}}{A_v^2} \\ &= \left(4kT \frac{2}{3} g_m + \frac{K}{C_{ox} W L} \cdot \frac{1}{f} \cdot g_m^2 + \frac{4kT}{R_D} \right) R_D^2 \frac{1}{g_m^2 R_D^2} \\ &= 4kT \frac{2}{3g_m} + \frac{K}{C_{ox} W L} \cdot \frac{1}{f} + \frac{4kT}{g_m^2 R_D} \end{aligned}$$

If only the noise voltage is attached at input,
for an infinite source impedance \rightarrow output noise = 0 : problem!

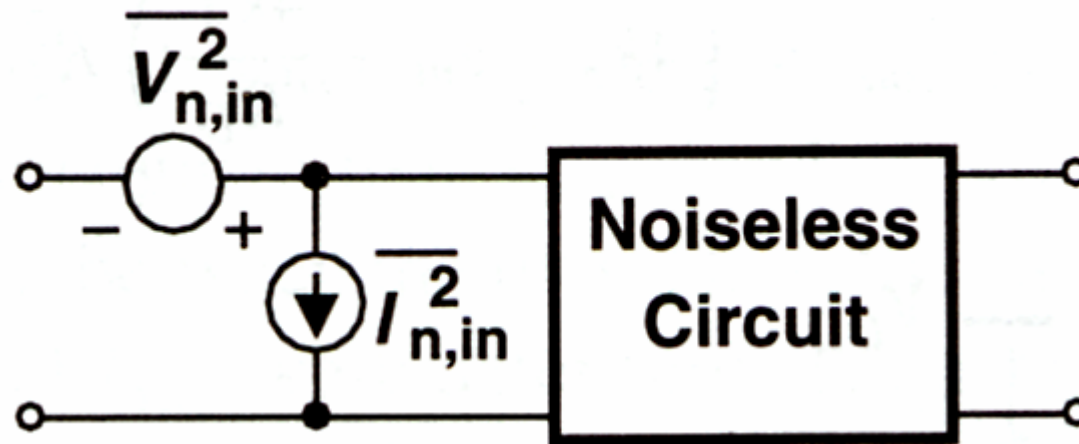


Source Impedance $Z_s = \text{infinity}$ (current source signal input)

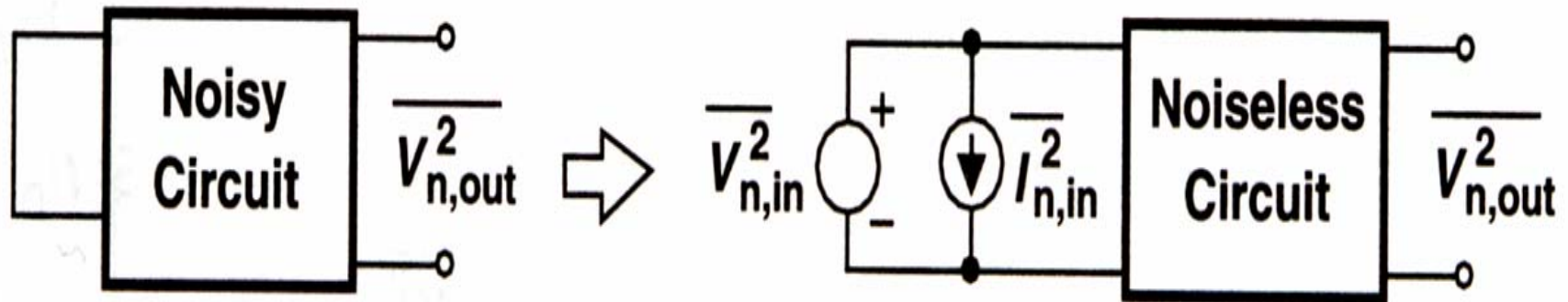


Noise output = 0 even with a non-zero input noise voltage $V_{n,in}$

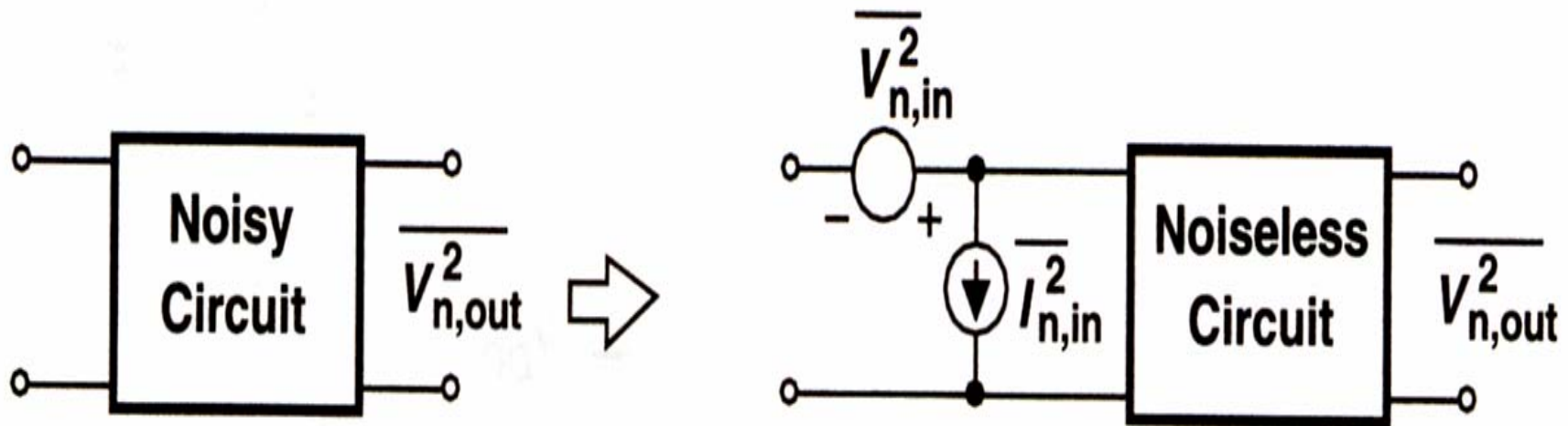
For a general case of source impedance, both a noise voltage and a noise current must be used.



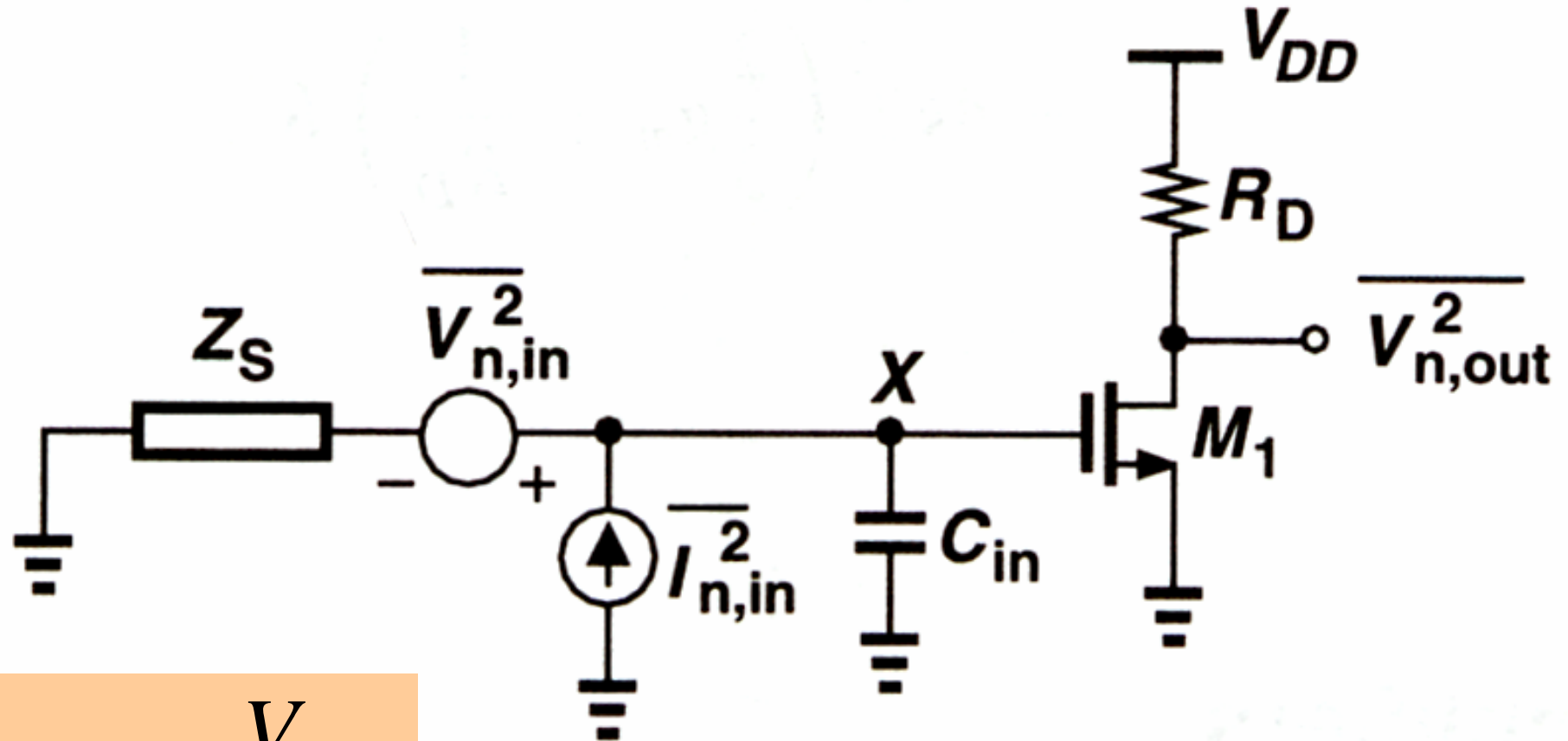
$I_{n.in}$ and $V_{n.in}$: correlated



$V_{n.in}$ can be calculated with $Z_S = 0$



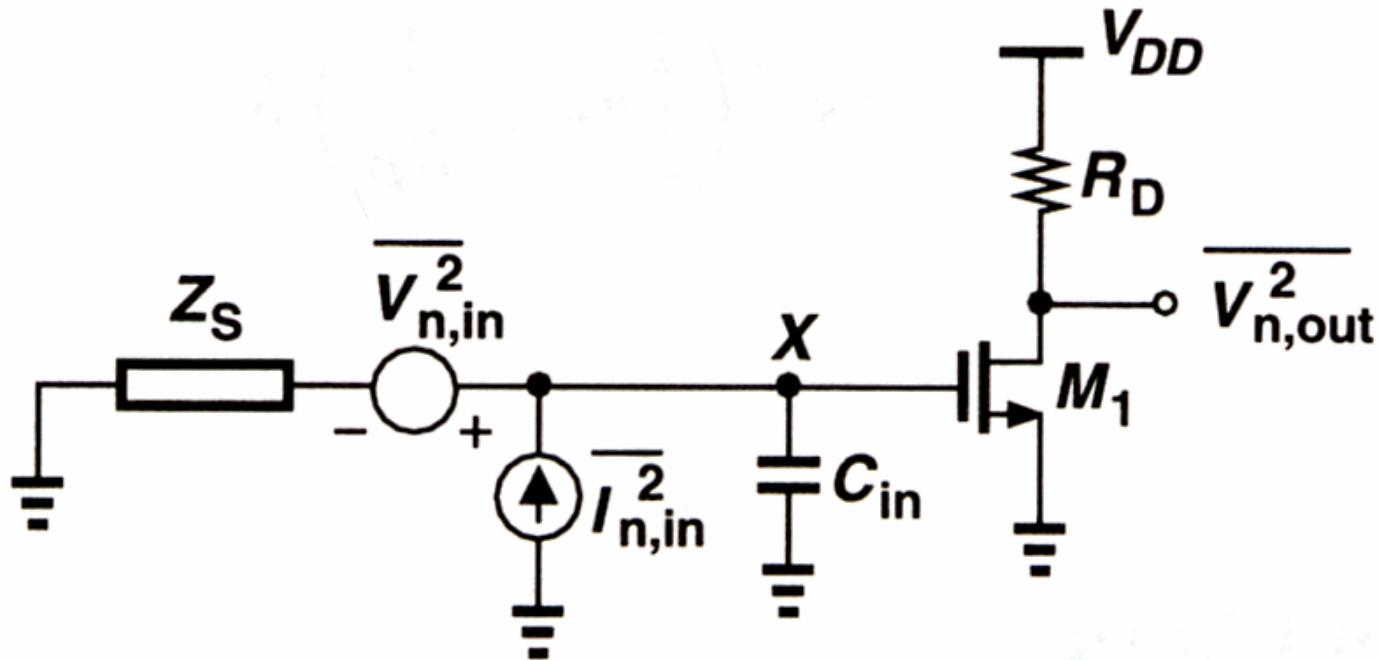
$I_{n.in}$ can be calculated with $Z_S = \infty$



$$I_{n.in} = \frac{V_{n.in}}{Z_{in}}$$

$I_{n.in}$ $V_{n.in}$: *correlated*

Holds for CS amp

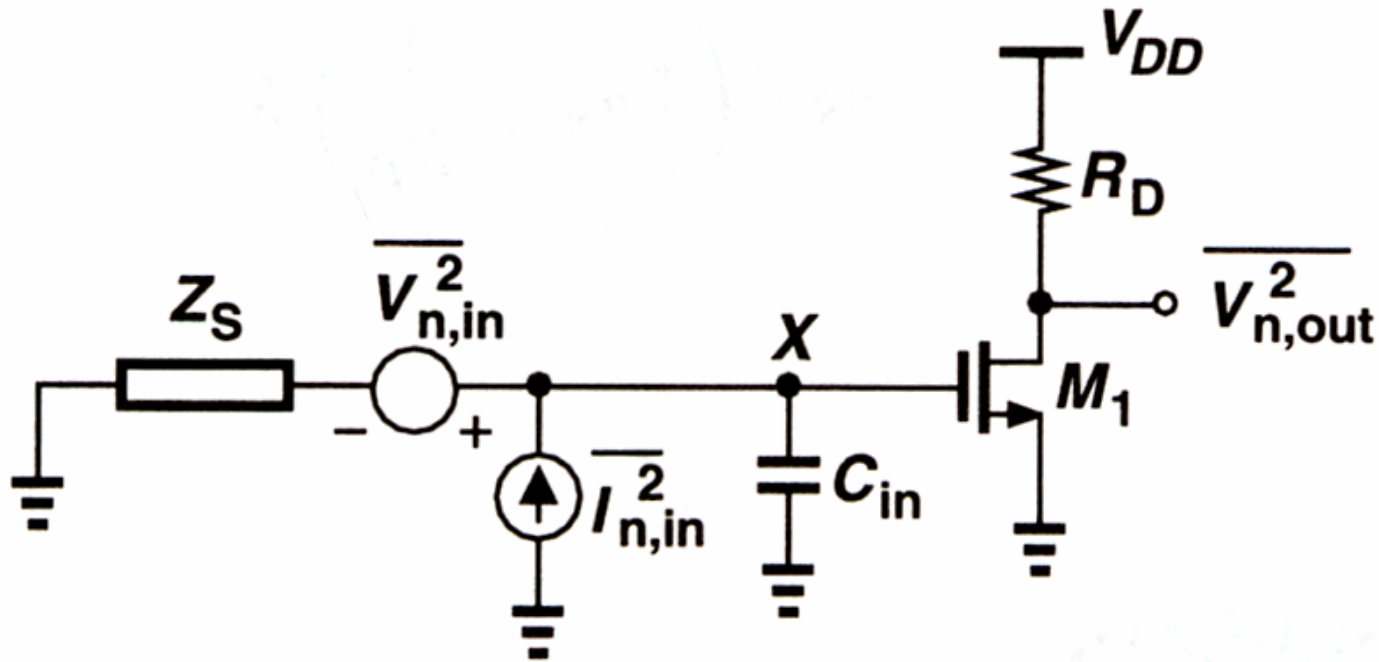


$$\overline{V_{n,in}^2} = \frac{\overline{V_{n,out}^2}}{A_v^2}$$

$V_{n.in}$ can be calculated with $Z_S = 0$

$$= \left(4kT \frac{2}{3} g_m + \frac{K}{C_{ox} WL} \cdot \frac{1}{f} \cdot g_m^2 + \frac{4kT}{R_D} \right) R_D^2 \frac{1}{g_m^2 R_D^2}$$

$$= 4kT \frac{2}{3g_m} + \frac{K}{C_{ox} WL} \cdot \frac{1}{f} + \frac{4kT}{g_m^2 R_D}$$

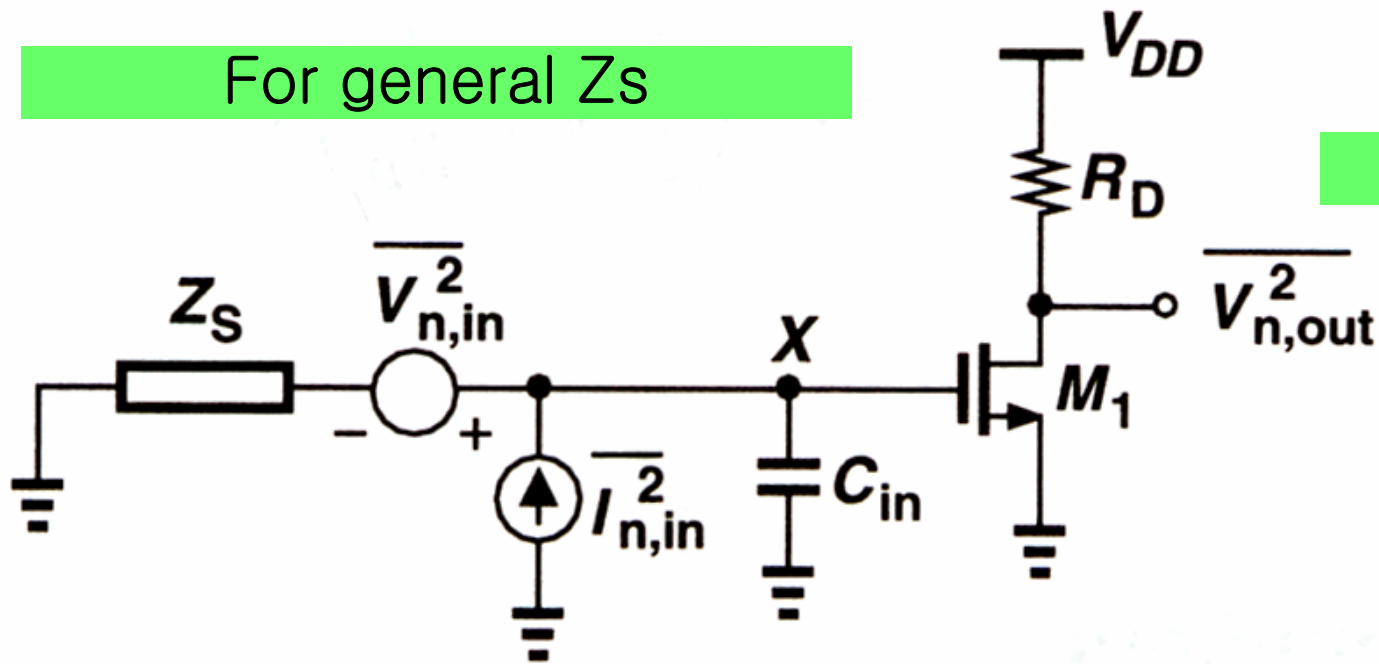


$I_{n.in}$ can be calculated with $Z_S = \infty$

$$I_{n.in} = \frac{V_{n.in}}{Z_{in}} = sC_{in} \cdot V_{n.in}$$

$V_{n.X} = V_{n.in}$ as desired

gives the same $V_{n.out}$

For general Z_S  $V_{n.in}$ $I_{n.in}$

Not double counted

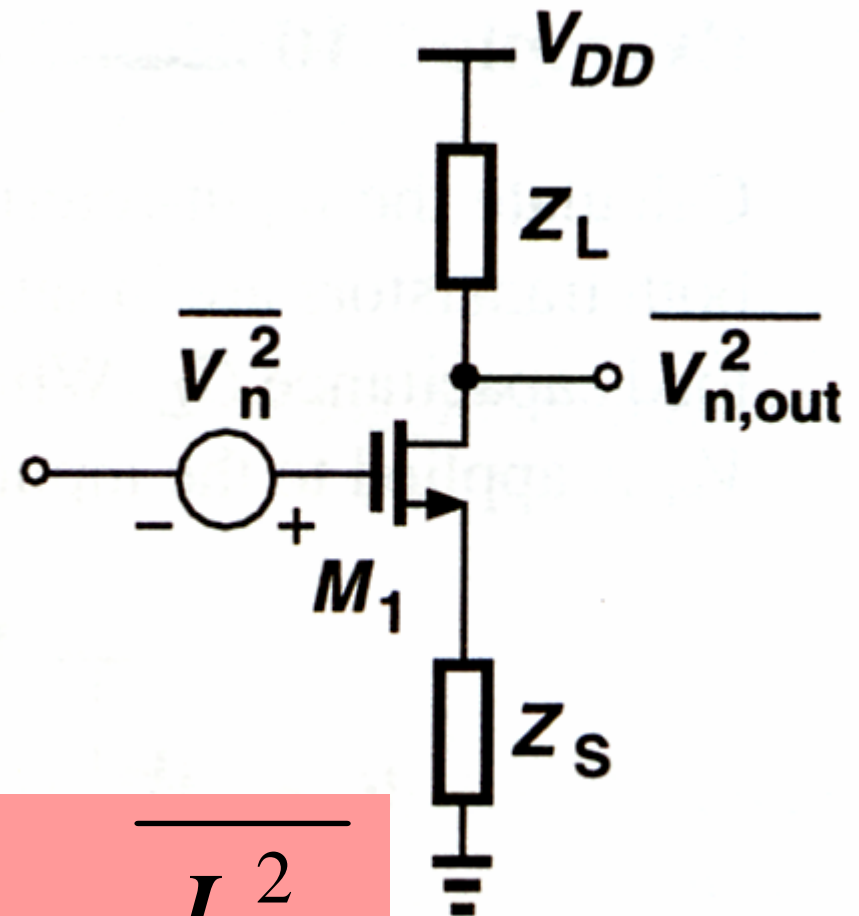
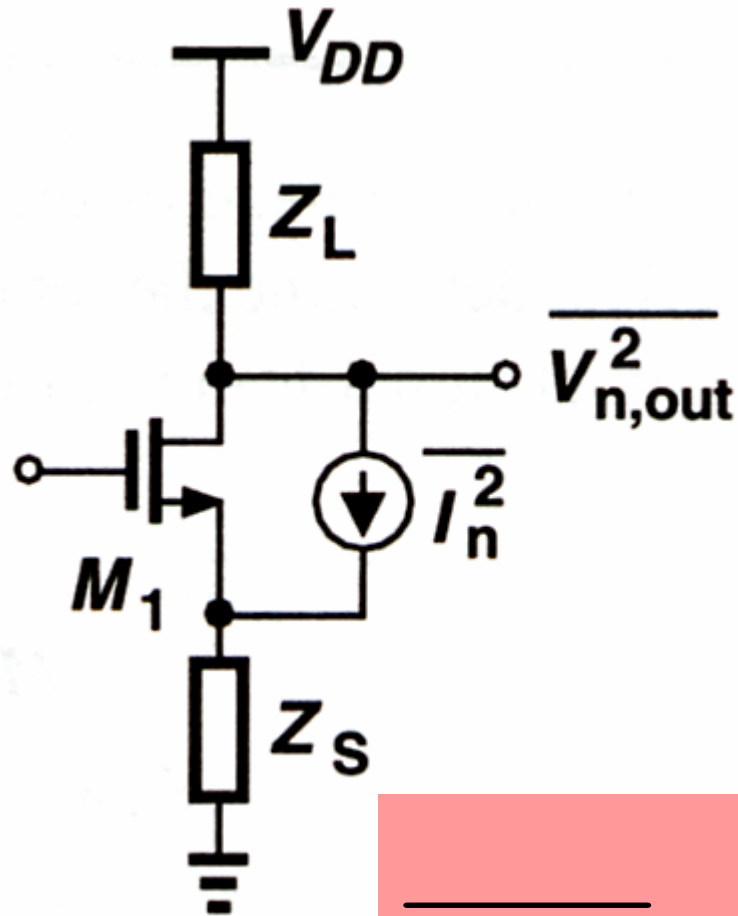
$$V_{n,X} = V_{n,in} \frac{\frac{1}{C_{in}s}}{\frac{1}{C_{in}s} + Z_S} + I_{n,in} \frac{\frac{Z_S}{C_{in}s}}{\frac{1}{C_{in}s} + Z_S}$$

$$= \frac{V_{n,in} + I_{n,in}Z_S}{Z_S C_{in}s + 1}$$

$$I_{n.in} = \frac{V_{n.in}}{Z_{in}} = sC_{in} \cdot V_{n.in}$$

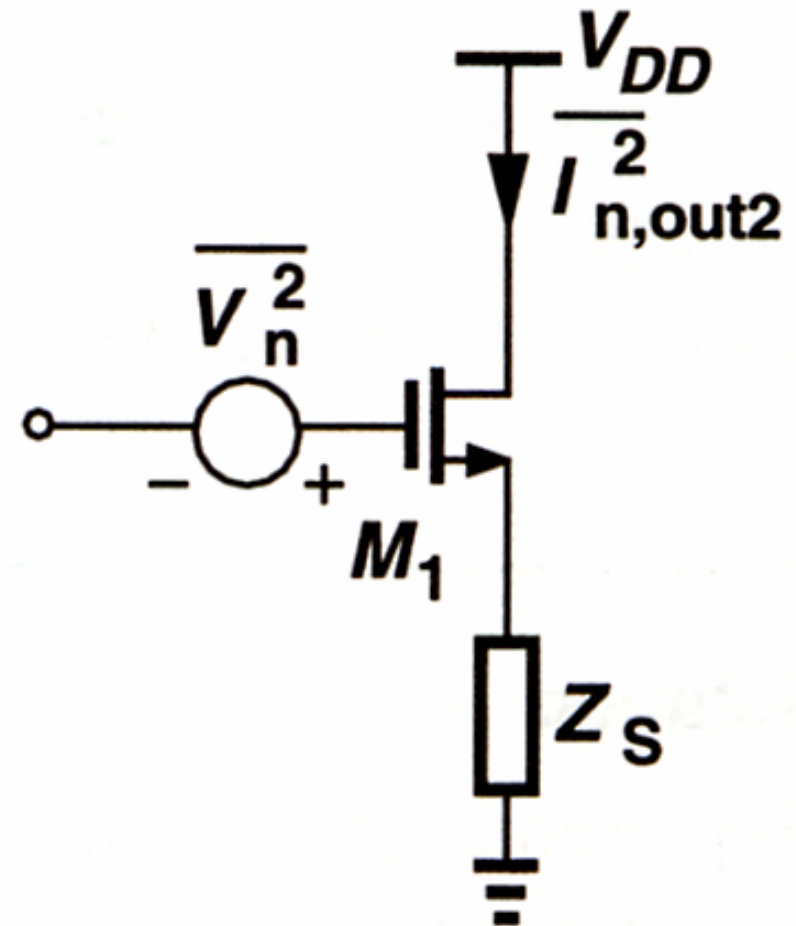
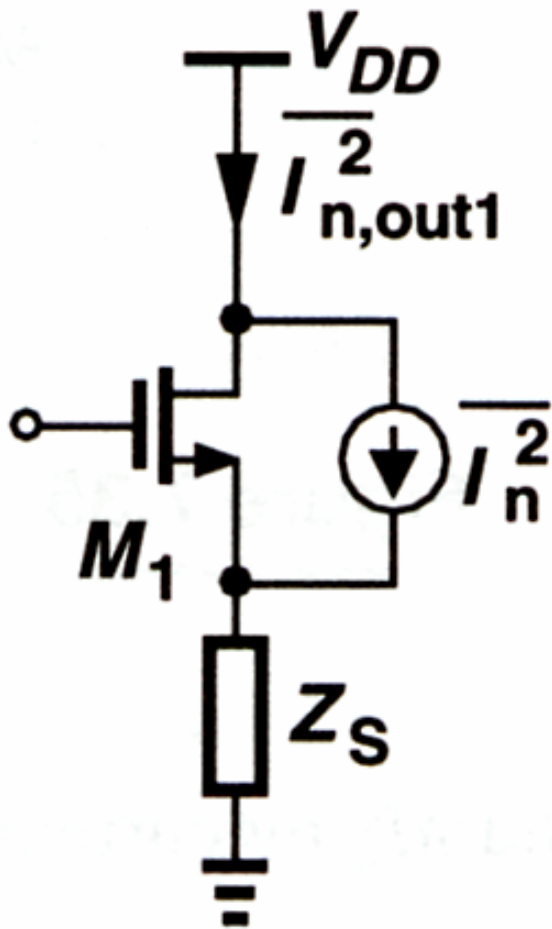
$$V_{n,X} = V_{n.in} \text{ as desired}$$

gives the same $V_{n.out}$



$$\overline{V_n^2} = \frac{\overline{I_n^2}}{g_m^2}$$

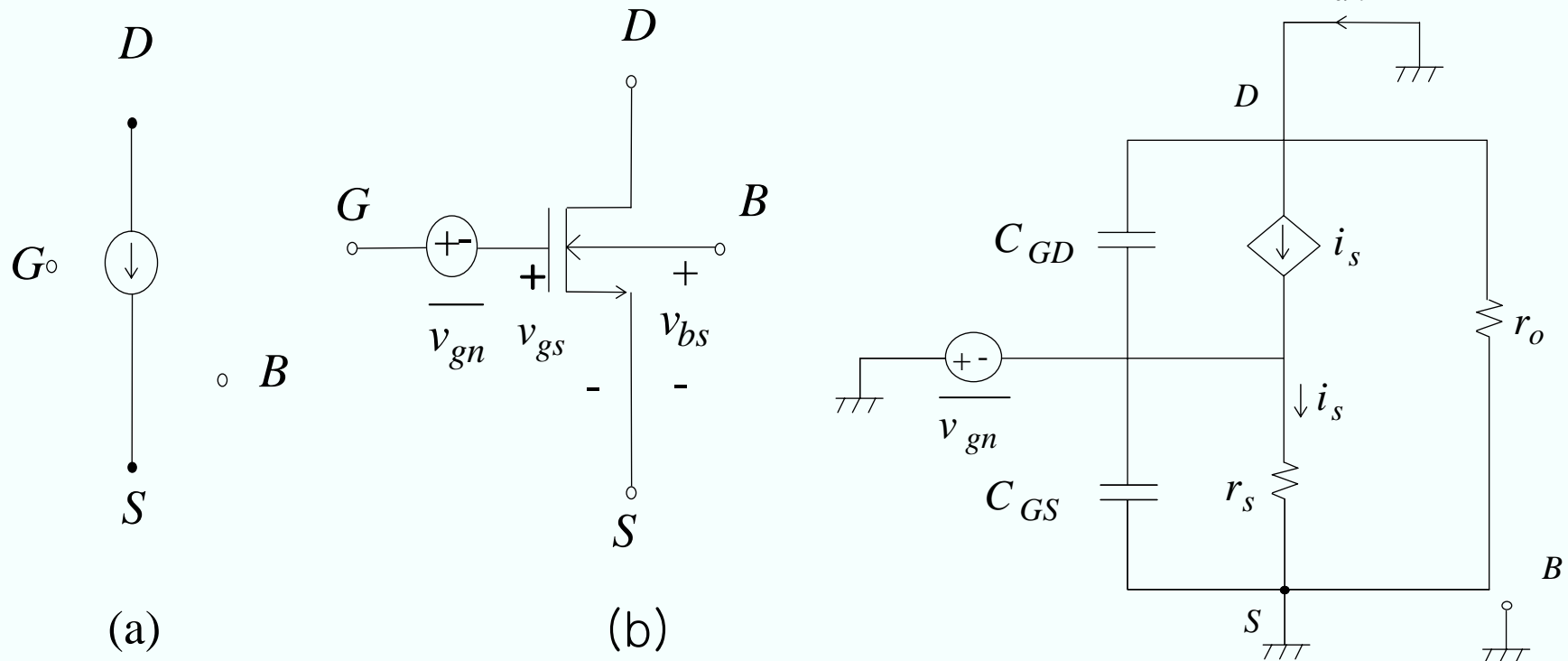
At low frequency



Proof of $\overline{V_n^2} = \frac{\overline{I_n^2}}{g_m^2}$

At low frequency

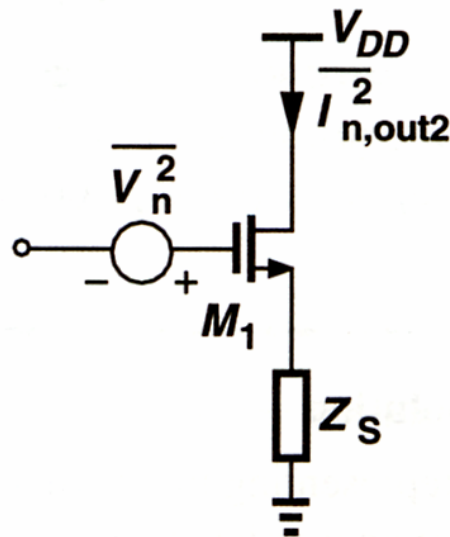
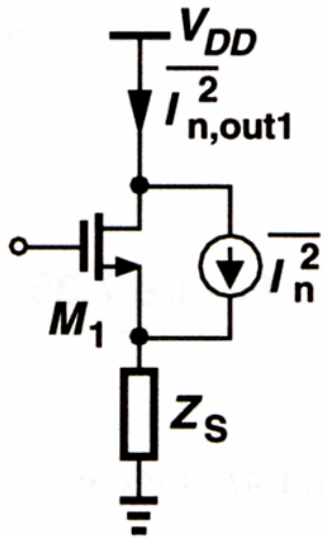
Simple proof for a source grounded MOSFET



$$\overline{i_{dn}} = -(g_m + j2\pi f \cdot C_{GD}) \cdot \overline{v_{gn}}$$

$$\overline{i_{dn}} \approx -g_m \cdot \overline{v_{gn}}$$

$$\overline{v_{gn}^2} = \frac{\overline{i_{dn}^2}}{g_m^2}$$



$$I_{n,out1} = \frac{I_n}{Z_s(g_m + 1/r_o) + 1}$$

$$I_{n,out2} = \frac{g_m V_n}{Z_s(g_m + 1/r_o) + 1}$$

Proof of $\overline{V_n^2} = \frac{\overline{I_n^2}}{g_m^2}$

At low frequency,

$$g_{mb} = 0$$

$$V_g = 0$$



$$\overline{V_n^2} = \frac{\overline{I_n^2}}{g_m^2}$$

$$I_{n,out2} = \frac{V_n}{\frac{1}{g_m} + \frac{1}{\frac{1}{Z_s} + \frac{1}{r_o}}} \times \frac{1}{\frac{1}{Z_s} + \frac{1}{r_o}}$$